



**AOP605**

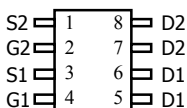
**Complementary Enhancement Mode Field Effect Transistor**

**General Description**

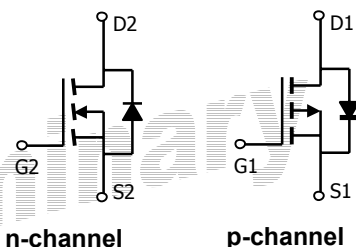
The AOP605 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs form a high-speed power inverter, suitable for a multitude of applications.

**Features**

n-channel	p-channel
$V_{DS} (V) = 30V$	-30V
$I_D = 7.5A$	-6.6A
$R_{DS(ON)} < 28m\Omega$	$< 35m\Omega (V_{GS} = 10V)$
$< 43m\Omega$	$< 58m\Omega (V_{GS} = 4.5V)$



PDIP-8



Preliminary

**Absolute Maximum Ratings  $T_A=25^\circ C$  unless otherwise noted**

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$T_A=25^\circ C$	7.5	-6.6	A
		$T_A=70^\circ C$	6	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	30	-30	
Power Dissipation	$T_A=25^\circ C$	2.5	2.5	W
	$T_A=70^\circ C$	1.6	1.6	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	$^\circ C$

**Thermal Characteristics: n-channel**

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	40	50	$^\circ C/W$
Maximum Junction-to-Ambient <sup>A</sup>		Steady-State	67	
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	33	40	$^\circ C/W$

**Thermal Characteristics: p-channel**

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	38	50	$^\circ C/W$
Maximum Junction-to-Ambient <sup>A</sup>		Steady-State	66	
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	30	40	$^\circ C/W$

n-channel MOSFET Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}$ , $V_{GS}=0\text{V}$	30			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}$ , $V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1	$\mu\text{A}$
					5	
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}$ , $V_{GS}=\pm 20\text{V}$			100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$	1	1.8	3	V
$I_{D(ON)}$	On state drain current	$V_{GS}=10\text{V}$ , $V_{DS}=5\text{V}$	30			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}$ , $I_D=7.5\text{A}$ $T_J=125^\circ\text{C}$		22.6	28	m $\Omega$
			$V_{GS}=4.5\text{V}$ , $I_D=6.0\text{A}$		33	
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}$ , $I_D=7.5\text{A}$	12	16		S
$V_{SD}$	Body Diode Forward Voltage	$I_S=1\text{A}$ , $V_{GS}=0\text{V}$		0.76	1	V
$I_S$	Maximum Body-Diode Continuous Current				4	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}$ , $V_{DS}=15\text{V}$ , $f=1\text{MHz}$		680		pF
$C_{oss}$	Output Capacitance.			102		pF
$C_{rss}$	Reverse Transfer Capacitance			77		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}$ , $V_{DS}=0\text{V}$ , $f=1\text{MHz}$		3		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=4.5\text{V}$ , $V_{DS}=15\text{V}$ , $I_D=7.5\text{A}$		13.84		nC
$Q_g$	Total Gate Charge			6.74		nC
$Q_{gs}$	Gate Source Charge			1.82		nC
$Q_{gd}$	Gate Drain Charge			3.2		nC
$t_{D(on)}$	Turn-On Delay Time	$V_{GS}=10\text{V}$ , $V_{DS}=15\text{V}$ , $R_L=2.0\Omega$ , $R_{GEN}=6\Omega$		4.6		ns
$t_r$	Turn-On Rise Time			4.1		ns
$t_{D(off)}$	Turn-Off Delay Time			20.6		ns
$t_f$	Turn-Off Fall Time			5.2		ns
$t_{rr}$	Body Diode Reverse Recovery time	$I_F=7.5\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$		16.5		ns
$Q_{rr}$	Body Diode Reverse Recovery charge	$I_F=7.5\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$		7.8		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any a given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using 80  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

p-channel MOSFET Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
B <sub>V</sub> DSS	Drain-Source Breakdown Voltage	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V	-30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			-1 -5	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> I <sub>D</sub> =-250μA	-1.2	-2	-2.4	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-5V	30			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> =-6.6A T <sub>J</sub> =125°C		28 37	35 45	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-5A		44	58	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =-5V, I <sub>D</sub> =-6.6A		13		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =-1A, V <sub>GS</sub> =0V		-0.76	-1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				-4.2	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-15V, f=1MHz		920		pF
C <sub>oss</sub>	Output Capacitance			190		pF
C <sub>riss</sub>	Reverse Transfer Capacitance			122		pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		3.6		Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g(10V)</sub>	Total Gate Charge (10V)	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V, I <sub>D</sub> =-6.6A		18.5		nC
Q <sub>g(4.5V)</sub>	Total Gate Charge (4.5V)			9.6		nC
Q <sub>gs</sub>	Gate Source Charge			2.7		nC
Q <sub>gd</sub>	Gate Drain Charge			4.5		nC
t <sub>D(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-15V, R <sub>L</sub> =2.3Ω, R <sub>GEN</sub> =3Ω		7.7		ns
t <sub>r</sub>	Turn-On Rise Time			5.7		ns
t <sub>D(off)</sub>	Turn-Off DelayTime			20.2		ns
t <sub>f</sub>	Turn-Off Fall Time			9.5		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-6.6A, dI/dt=100A/μs		20		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-6.6A, dI/dt=100A/μs		8.8		nC

A: The value of R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t<sub>θ</sub> ≤ 10s thermal resistance rating.

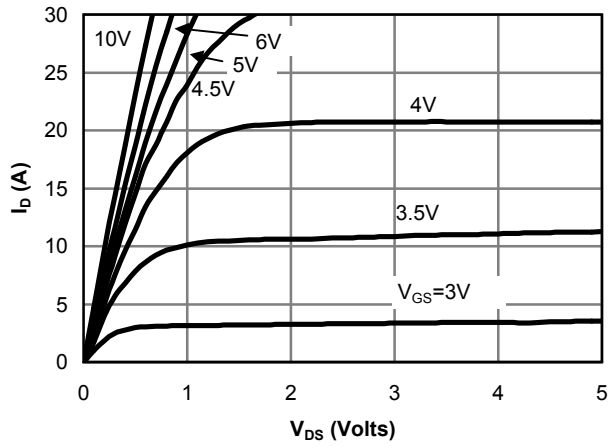
B: Repetitive rating, pulse width limited by junction temperature.

C. The R<sub>θJA</sub> is the sum of the thermal impedance from junction to lead R<sub>θJL</sub> and lead to ambient.

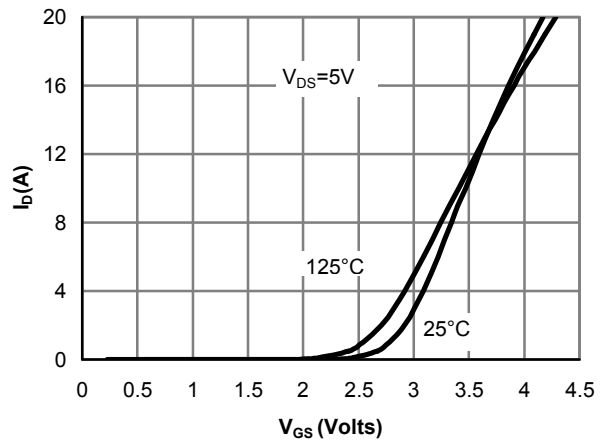
D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The SOA curve provides a single pulse rating.

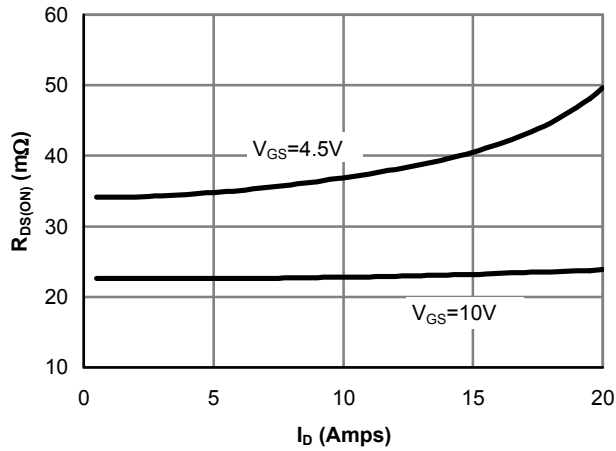
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: N-CANNEL**



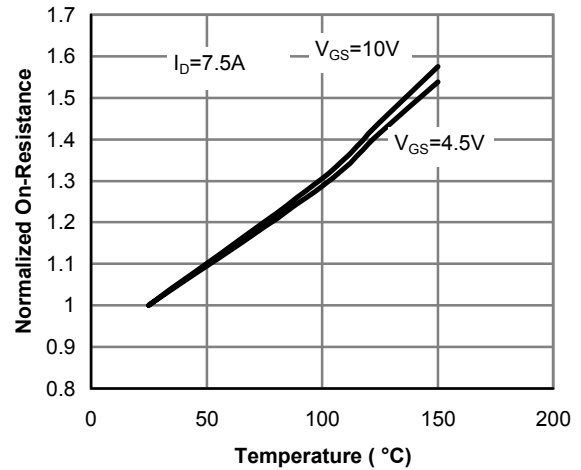
**Fig 1: On-Region Characteristics**



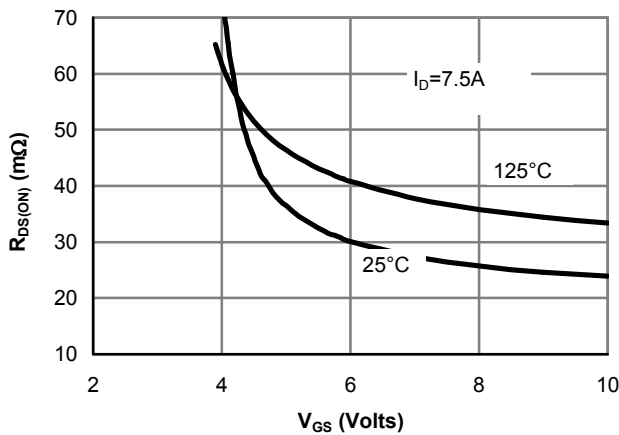
**Figure 2: Transfer Characteristics**



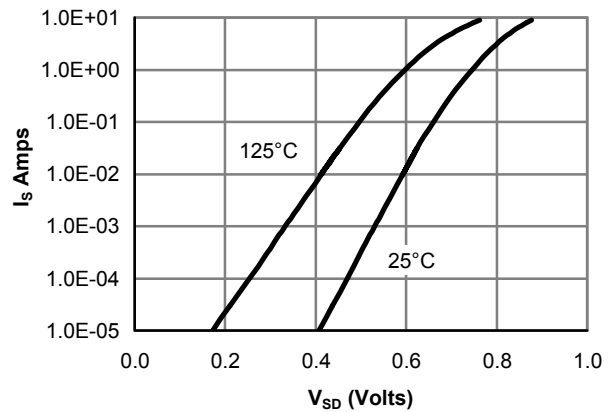
**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**



**Figure 4: On-Resistance vs. Junction Temperature**



**Figure 5: On-Resistance vs. Gate-Source Voltage**



**Figure 6: Body diode characteristics**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: N-CHANNEL**

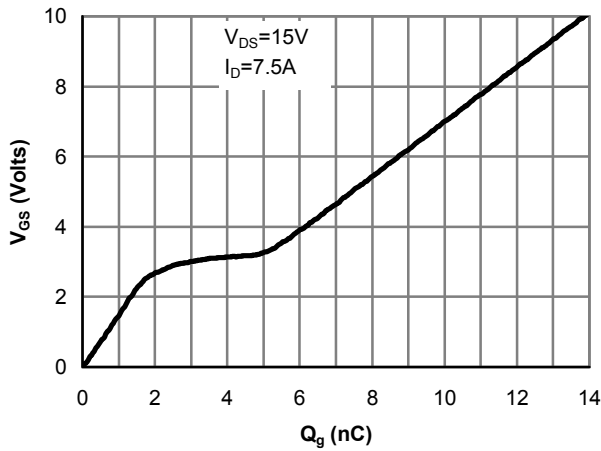


Figure 7: Gate-Charge characteristics

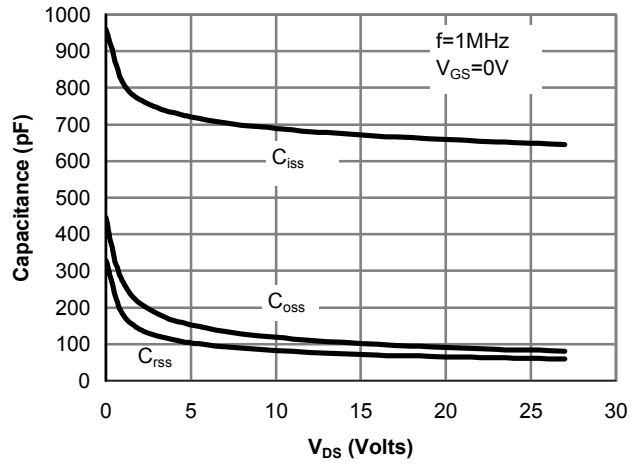


Figure 8: Capacitance Characteristics

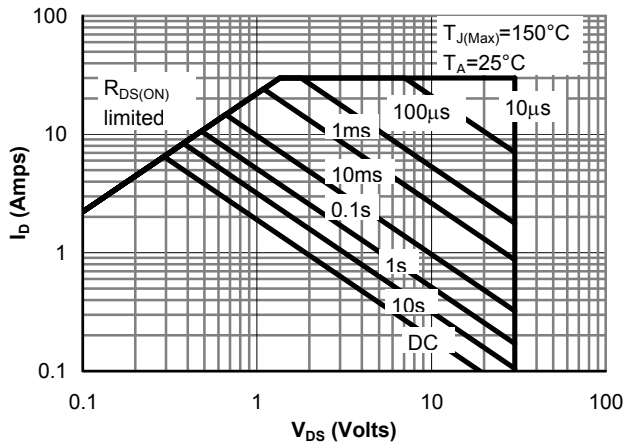


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

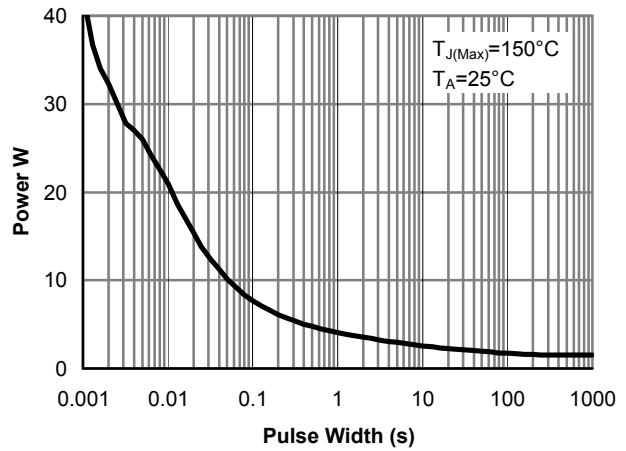


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

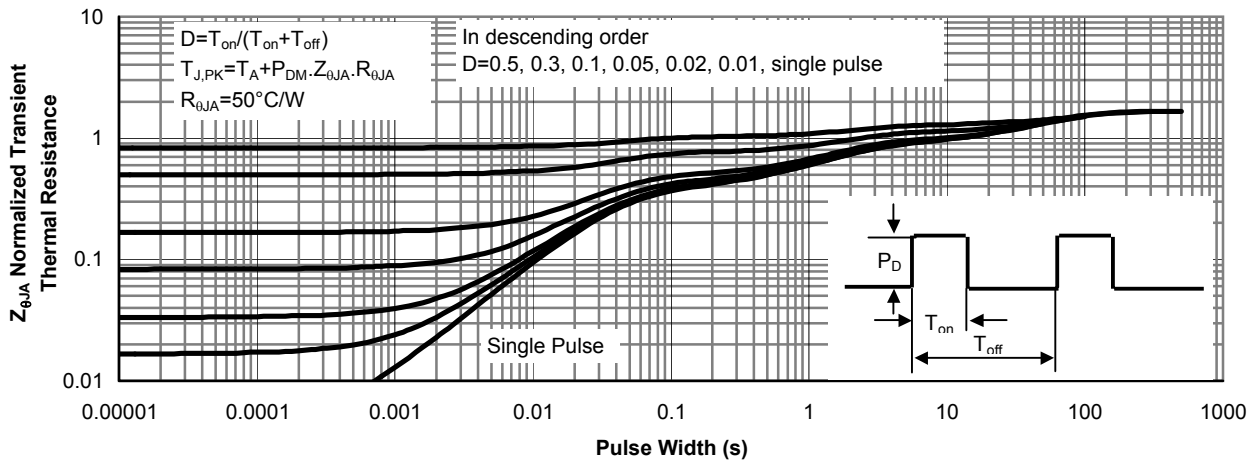


Figure 11: Normalized Maximum Transient Thermal Impedance

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

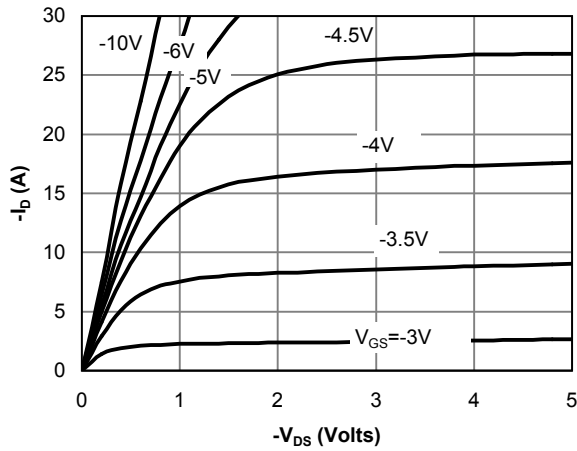


Fig 1: On-Region Characteristics

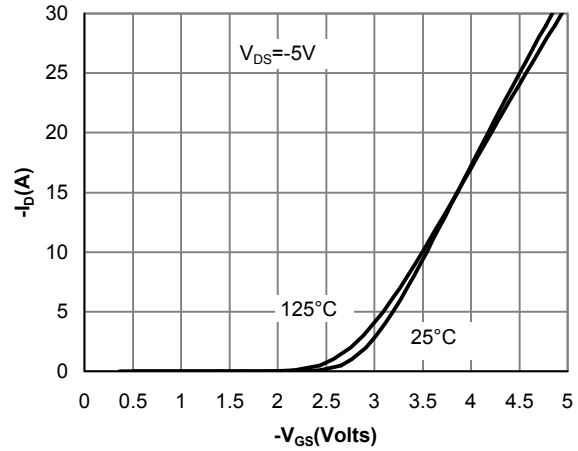


Figure 2: Transfer Characteristics

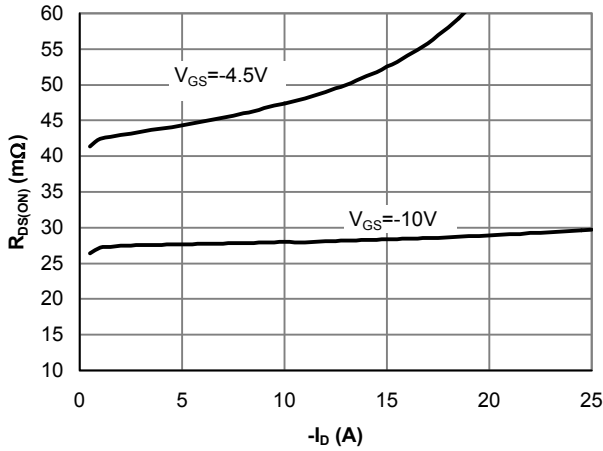


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

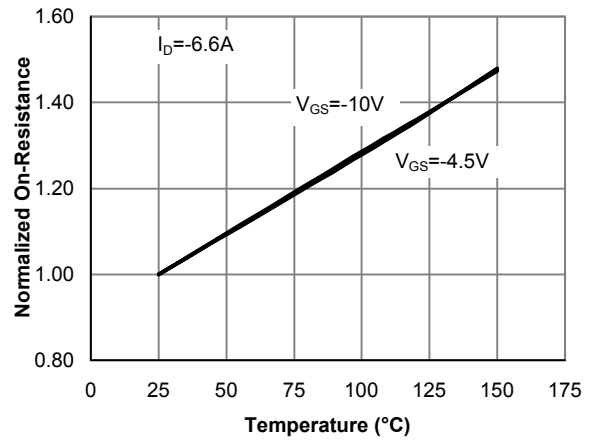


Figure 4: On-Resistance vs. Junction Temperature

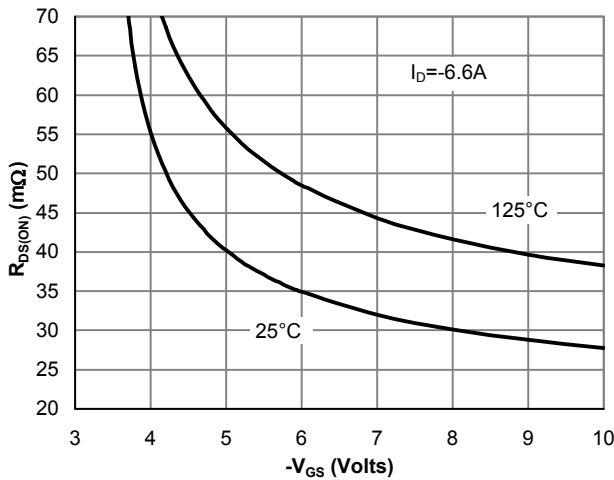


Figure 5: On-Resistance vs. Gate-Source Voltage

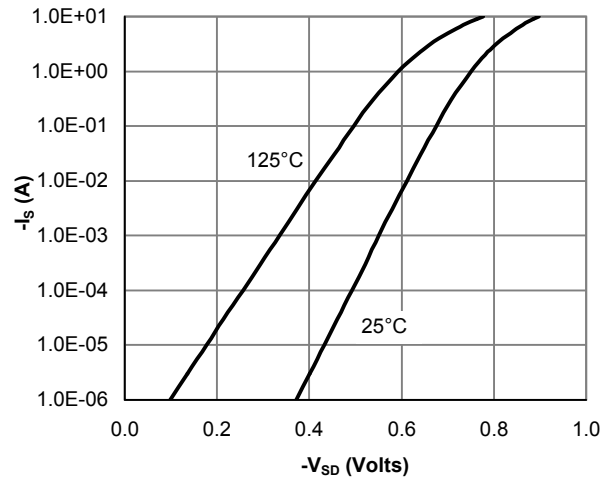


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

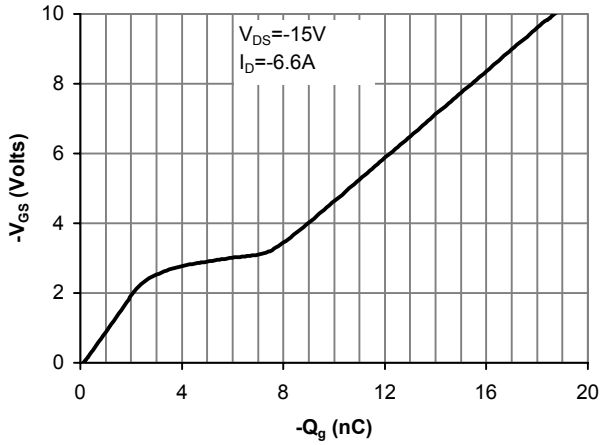


Figure 7: Gate-Charge Characteristics

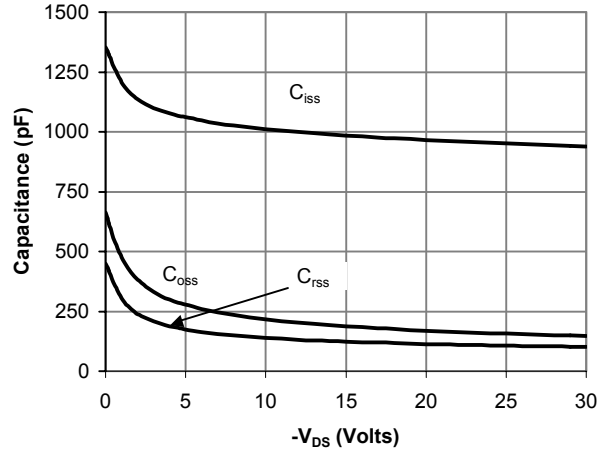


Figure 8: Capacitance Characteristics

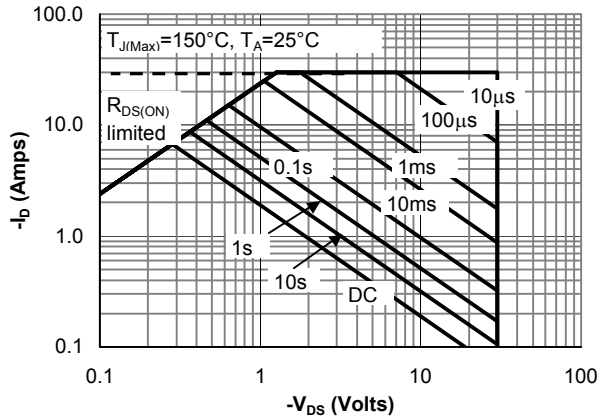


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

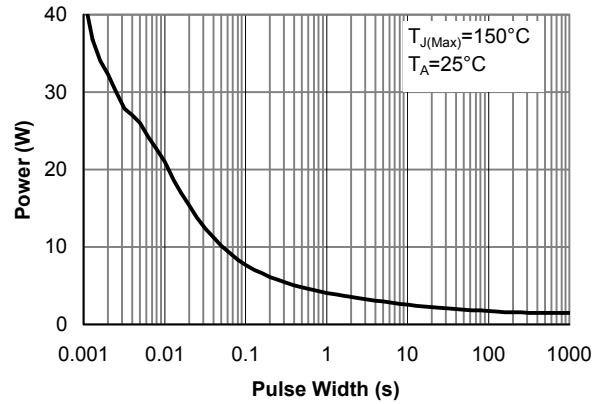


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

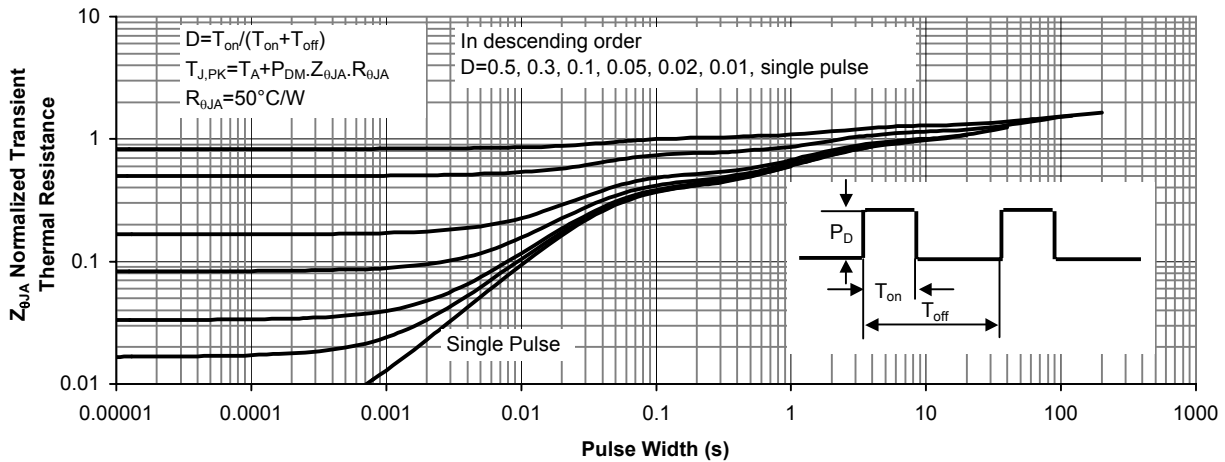


Figure 11: Normalized Maximum Transient Thermal Impedance



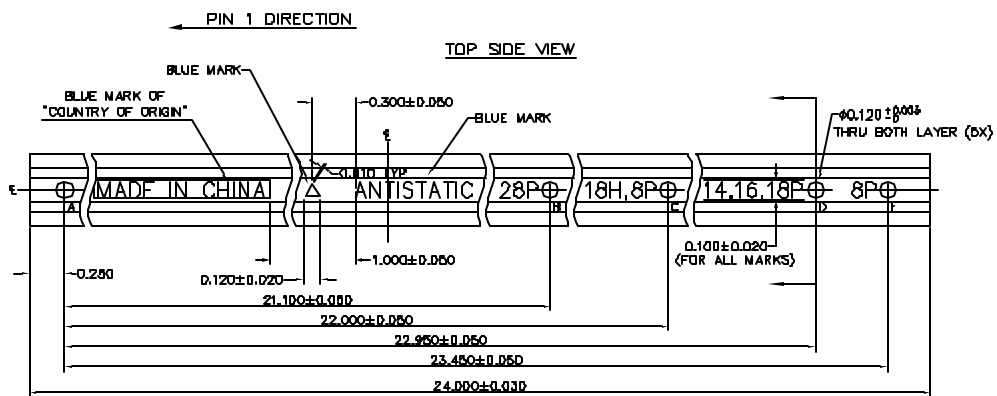




**ALPHA & OMEGA**  
SEMICONDUCTOR, INC.

**PDIP-8 (300) Tube Data**

PDIP-8 Tube



**NOTES:**

1. PLASTIC CARRIER THERMAL REQUIREMENTS TO 125F WITHOUT DISTORTION OR DETERIORATION IN ANTI-STATIC PROPERTIES.
2. CLARITY : PARTS IN TUBE TO BE CLEARLY VISIBLE IN DAYLIGHT TO THE NAKED EYE.
3. TUBE TO BE COATED (INSIDE AND OUT) WITH ANTI-STATIC AGENTS (PI-23820) AND THE SURFACE RESISTIVITY SHALL BE BETWEEN  $10^8$  TO  $10^{12}$  OHM/CM<sup>2</sup>.
4. MAT'L : MODIFIED ACRYLIC OR RIGID PVC.
5. FLATNESS : TUBE TO BE FLAT WITH 1/32 INCH.
6. BLUE MARK OF "Δ ANTISTATIC 28P 8P 14, 16, 18P" SHALL BE PUT ON TOP SURFACE OF TUBE AND SHALL PASS COTTON BRUSH TEST. (5 CYCLES)\*
7. TUBE WITH RIPPLE SURFACE AT PACKAGE LOADING AREA THAT AFFECT PACKAGE VISIBILITY SHALL BE REJECTABLE.
8. ALL DIMENSION ARE IN INCH.

